

Announcement from Editorial Board

The following article has been retracted due to the fact that the authors practise fraud. The scientific community takes a very strong view on this matter, and the **Advances in Materials Physics and Chemistry** treats all unethical behavior seriously. This paper published in **Vol. 4 No. 10 194-202, 2014** has been removed from this site.

Title: Investigation on the Effect of Film Thickness on the Surface Morphology, Electrical and Optical Properties of E-Beam Deposited Indium Tin Oxide (ITO) Thin Film

Authors: Golam Saklayen, Shahinul Islam, Ferdous Rahman, Abu Bakar Ismail

AMPC Editorial Board

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